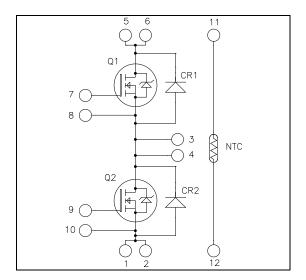


## Phase leg SiC MOSFET Power Module

$$\begin{split} V_{DSS} &= 1700 V \\ R_{DSon} &= 60 m \Omega \text{ max @ Tj} = 25^{\circ} C \\ I_{D} &= 53 A \text{ @ Tc} = 25^{\circ} C \end{split}$$



### **Application**

- Welding converters
- Switched Mode Power Supplies
- Uninterruptible Power Supplies
- Motor control

#### **Features**

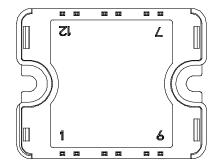
- SiC Power MOSFET
  - High speed switching
  - Low R<sub>DS(on)</sub>
  - Ultra low loss

#### • SiC Schottky Diode

- Zero reverse recovery
- Zero forward recovery
- Temperature Independent switching behavior
- Positive temperature coefficient on VF
- Very low stray inductance
- Kelvin source for easy drive
- Internal thermistor for temperature monitoring
- High level of integration
- AlN substrate for improved thermal performance

#### **Benefits**

- Outstanding performance at high frequency operation
- Direct mounting to heatsink (isolated package)
- Low junction to case thermal resistance
- Solderable terminals both for power and signal for easy PCB mounting
- Low profile
- RoHS Compliant



Pins 1/2; 3/4; 5/6 must be shorted together

#### All ratings (a) $T_i = 25$ °C unless otherwise specified

#### Absolute maximum ratings (per SiC MOSFET)

Symbol	Parameter		Max ratings	Unit
$V_{ m DSS}$	Drain - Source Voltage		1700	V
Ţ	Continuous Drain Current	$T_c = 25^{\circ}C$	53	
$I_{D}$	Continuous Diam Current	$T_c = 80$ °C	40	Α
$I_{DM}$	Pulsed Drain current		110	
$V_{GS}$	Gate - Source Voltage		-10/25V	V
$R_{DSon}$	Drain - Source ON Resistance		60	mΩ
$P_{\mathrm{D}}$	Maximum Power Dissipation	$T_c = 25^{\circ}C$	350	W

CAUTION: These Devices are sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed. See application note APT0502 on www.microsemi.com



## **Electrical Characteristics** (per SiC MOSFET)

Symbol	Characteristic	Test Conditions		Min	Тур	Max	Unit
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{GS} = 0V$ , $V_{DS} = 1700V$				100	μA
D	Drain – Source on Resistance	$V_{GS} = 20V$	$T_j = 25^{\circ}C$		40	60	
$R_{DS(on)}$		$I_D = 50A$	$T_j = 150$ °C		80		mΩ
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = 2.5 \text{mA}$		1.9	2.3		V
$I_{GSS}$	Gate – Source Leakage Current	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$				500	nA

### **Dynamic Characteristics** (per SiC MOSFET)

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
$C_{iss}$	Input Capacitance	$V_{GS} = 0V$			3080		
$C_{oss}$	Output Capacitance	$V_{DS} = 1000V$			165		pF
$C_{rss}$	Reverse Transfer Capacitance	f = 1MHz			16		
$Q_{g}$	Total gate Charge	$V_{GS} = -5/+20V$			190		nC
$Q_{gs}$	Gate – Source Charge	$V_{Bus} = 1000V$			37		
$Q_{gd}$	Gate – Drain Charge	$I_D = 20A$			70		
$T_{d(on)}$	Turn-on Delay Time	$\begin{array}{l} -V_{GS} = -5/+20V \\ V_{Bus} = 1000V \\ I_D = 50A \; ; \; T_J = 150^{\circ}C \\ R_L = 20\Omega \; ; \; R_{Gext} = 20\Omega \end{array}$			35		
$T_{\rm r}$	Rise Time				40		ns
$T_{d(off)}$	Turn-off Delay Time				150		
$T_{\mathrm{f}}$	Fall Time				70		
Eon	Turn on Energy	Inductive Switching $V_{GS} = -5/+20V$ $V_{Bus} = 1000V$	$T_j = 150^{\circ}C$		1.9		mJ
$E_{\text{off}}$	Turn off Energy	$I_{D} = 50A$ $R_{Gext} = 20\Omega$	$T_j = 150^{\circ}C$		1.2		1113
$R_{\text{Gint}}$	Internal gate resistance				1.5		Ω
$R_{thJC}$	Junction to Case Thermal Resistance	ee				0.36	°C/W

### **Source - Drain diode ratings and characteristics** (per SiC MOSFET)

Symbol	Characteristic	Test Conditions	Min	Тур	Max	Unit	
$V_{SD}$	Diode Forward Voltage $ V_{GS} = -5V, I_{SD} = 25A $ $V_{GS} = -2V, I_{SD} = 25A $	$V_{GS} = -5V, I_{SD} = 25A$		3.5		V	
		$V_{GS} = -2V, I_{SD} = 25A$		3.1		V	
$t_{rr}$	Reverse Recovery Time	$I_{SD} = 25A \; ; \; V_{GS} = -5V \ V_R = 1000V \; ; \; di_F/dt = 100A/\mu s$		TBD		ns	
$Q_{rr}$	Reverse Recovery Charge			TBD		μC	
$I_{rr}$	Reverse Recovery Current			TBD		Α	

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### SiC schottky diode ratings and characteristics (per SiC diode)

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
$V_{RRM}$	Peak Repetitive Reverse Voltage					1700	V
T	December Leeler of Comment	$V_{R}=1700V$	$T_j = 25$ °C		20	100	^
$I_{RRM}$	Reverse Leakage Current	V <sub>R</sub> -1/00 V	$T_{j} = 175^{\circ}C$		100	400	μA
$I_{F}$	DC Forward Current		Tc = 125°C		25		A
$V_{\mathrm{F}}$	Diode Forward Voltage	In = 25A	$T_i = 25$ °C		1.8	2	V
V F	Diode Polward Voltage		$T_{i} = 175^{\circ}C$		3.2	4	•
$Q_{\rm C}$	Total Capacitive Charge	$I_F = 25A, V_R = 1700V$ di/dt = $400A/\mu s$			170		nC
С	Total Conseitence	$f = 1 MHz, V_R =$	= 200V		200		рF
	Total Capacitance	$f = 1MHz, V_R = 400V$			140		pr.
$R_{thJC}$	Junction to Case Thermal Resistance	_				0.48	°C/W

## $\label{thm:complex} \textbf{Temperature sensor NTC} \ \ (\text{see application note APT0406 on www.microsemi.com}).$

Sj	ymbol	Characteristic		Min	Typ	Max	Unit
	R <sub>25</sub>	Resistance @ 25°C			50		kΩ
$\Delta l$	$R_{25}/R_{25}$				5		%
	B <sub>25/85</sub>	$T_{25} = 298.15 \text{ K}$			3952		K
1	ΔΒ/Β		T <sub>C</sub> =100°C		4		%

$$R_{T} = \frac{R_{25}}{\exp \left[ B_{25/85} \left( \frac{1}{T_{25}} - \frac{1}{T} \right) \right]} \quad \text{T: Thermistor temperature}$$
 
$$R_{T}: \text{ Thermistor value at T}$$

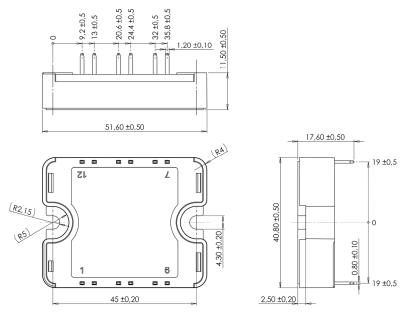
### Thermal and package characteristics

Symbol	Characteristic			Min	Max	Unit
$V_{ISOL}$	RMS Isolation Voltage, any terminal to case t =1 min, 50/60Hz					V
Т	Operating junction temperature range  SiC MOSFET		SFET	-40	150	
$T_{J}$	Operating junction temperature range	SiC di	ode	-40	175	
$T_{JOP}$	Recommended junction temperature under switching conditions				T <sub>J</sub> max -25	°C
$T_{STG}$	Storage Temperature Range				125	
$T_{\rm C}$	Operating Case Temperature	-40	100			
Torque	Mounting torque	To heatsink M4		2	3	N.m
Wt	Package Weight				80	g

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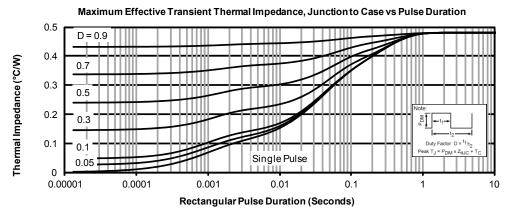


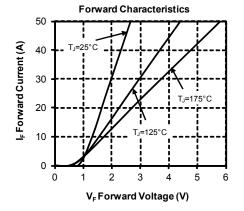
### Package outline (dimensions in mm)

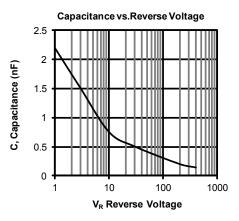


See application note 1904 - Mounting Instructions for SP1 Power Modules on www.microsemi.com

### Typical SiC diode Performance Curve

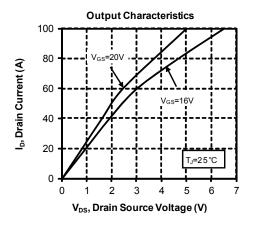


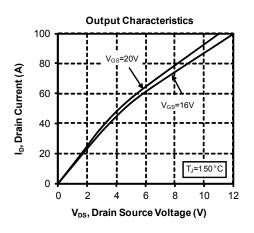


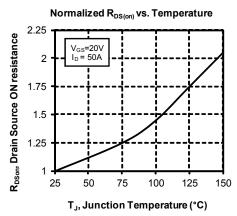


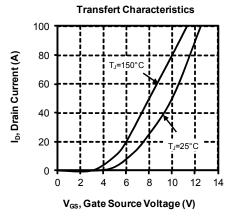


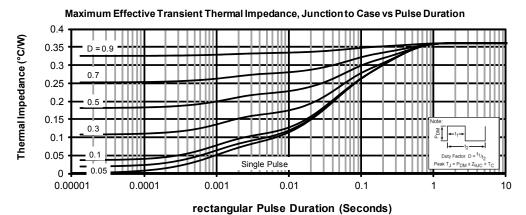
### **Typical SiC MOSFET Performance Curve**



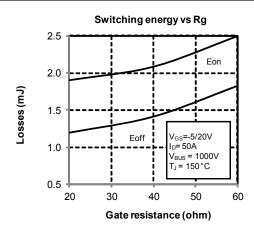


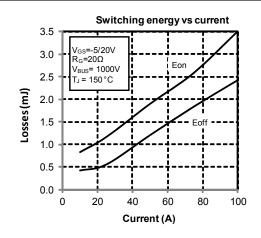


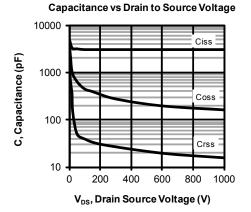


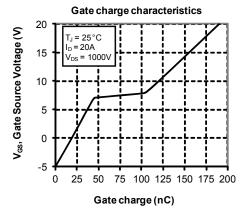


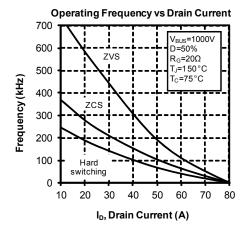














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